



Office of the Controller General of Patents, Designs & Trade Marks
Department of Industrial Policy & Promotion,
Ministry of Commerce & Industry,
Government of India

सत्यमेव जयते

Application Details

APPLICATION NUMBER	5558/CHE/2015
APPLICATION TYPE	ORDINARY APPLICATION
DATE OF FILING	16/10/2015
APPLICANT NAME	SREENIDHI INSTITUTE OF SCIENCE AND TECHNOLOGY
TITLE OF INVENTION	Fault Mapping Technique for Efficient Memory Utilization with Selectable Imprecision
FIELD OF INVENTION	COMPUTER SCIENCE
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PRIORITY DATE	
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